Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/752,073	SCHIER, JOHN E.
Examiner	Art Unit
Tri H. Phan	2661

SEARCHED					
Class	Subclass	Date	Examiner		
375	88.13, 201.01, 201.02, 201.05	6/30/2004	TP		
370	493-495	6/30/2004	TP		
370	419	6/30/2004	TP		
375	222	3/23/2005	TP		
713	200-202	3/23/2005	TP		
Updated	search	10/28/2005	TP		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST, IEEE, Internet search	6/30/2004	TP		
Consulted with Brian Nguyen (Pri)	3/23/2005	ТР		
Consulted with Frank Duong (Pri)	10/28/2005	TP		
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